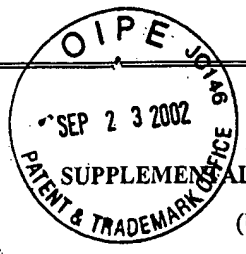


#5



**SUPPLEMENTAL INFORMATION DISCLOSURE CITATION**  
(Use several sheets if necessary)

ATTY. DOCKET NO. 44046.203.187.1	SERIAL NO. 10/071,420
APPLICANT Cardinal Glass Industries, Inc.	
FILING February 8, 2002	GROUP 3723

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DVN	5,626,911 ✓	05/06/97	Bertin, et al.	427	271	
↓	5,934,982 ✓	08/10/99	Vianello, et al.	451	44	
↓	4,716,686 ✓	01/05/88	Lisec	51	76R	

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
DVN	DE4419963C ✓	06/08/94	Germany	B24B9	10		X
↓	EP0709348 A1 ✓	10/16/95	Europe	C03C 23	00	X	
↓	DE3800732 A1 ✓	01/13/88	Germany	C03B 33	02		X
↓	EP1167312 A1 ✓	06/26/01	Europe	C03C 17	00	X	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**


EXAMINER <i>Imy van hygen</i>	DATE CONSIDERED 11-20-2003	RECEIVED SEP 26 2002 TECHNOLOGY CENTER
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<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				ATTY. DCK NO. 44046.200187.1		SERIAL NO. 10/071,420	
				APPLICANT Valek, et al.			
				FILING 08 February 2002		GROUP 3723	

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
JVN          	6,210,779 ✓	03 Apr 2001	Watanabe et al.				
	6,191,062 ✓	20 Feb 2001	Hayakawa et al.				
	6,165,256 ✓	26 Dec 2000	Hayakawa et al.				
	6,139,803 ✓	31 Oct 2000	Watanabe et al.				
	6,090,489 ✓	18 Jul 2000	Hayakawa et al.				
	6,013,372 ✓	11 Jan 2000	Hayakawa et al.				
	5,961,843 ✓	05 Oct 1999	Hayakawa et al.				
	5,939,194 ✓	27 Aug 1999	Hashimoto et al.				
	5,934,982 ✓	10 Aug 1999	Vianello et al.				
	5,874,701 ✓	23 Feb 1999	Watanabe et al.				
5,854,169 ✓	29 Dec 1998	Heller et al.					
5,853,866 ✓	29 Dec 1998	Watanabe et al.					

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
					YES	NO	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	

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				APPLICANT Valek et al.			
				FILING February 8, 2002		GROUP 3723	

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 MAY 29 2002  
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
DVN ↓	5,849,200 ✓	15 Dec 1998	Heller et al.			RECEIVED JUN - 3 2002 TECHNOLOGY CENTER R3703	
	5,698,262 ✓	16 Dec 1997	Soubeyrand et al.				
	5,616,532 ✓	01 Apr 1997	Heller et al.				
	5,547,825 ✓	20 Aug 1996	Takahashi et al.				
	5,424,130 ✓	13 Jun 1995	Nakanishi et al.				
	5,394,269 ✓	28 Feb 1995	Takamatsu et al.				
	4,716,686 ✓	05 Jan 1988	Lisec				
	4,166,018 ✓	28 Aug 1979	Chapin				

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
					YES	NO	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		

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